



FQH44N10_F133

100V N-Channel MOSFET

General Description

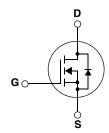
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as audio amplifier, high efficiency switching DC/DC converters, and DC motor control.

Features

- 48A, 100V, $R_{DS(on)}$ = 0.039 Ω @V_{GS} = 10 V Low gate charge (typical 48 nC)
- Low Crss (typical 85 pF)
- · Fast switching
- · 100% avalanche tested
- · Improved dv/dt capability
- · 175°C maximum junction temperature rating





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQH44N10_F133	Units	
V_{DSS}	Drain-Source Voltage		100	V	
I _D	Drain Current - Continuous (T _C = 25°	C)	48	Α	
	- Continuous (T _C = 100°C)		34	Α	
I _{DM}	Drain Current - Pulsed	(Note 1)	192	Α	
V _{GSS}	Gate-Source Voltage		± 25	V	
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	530	mJ	
I _{AR}	Avalanche Current	(Note 1)	48	Α	
E _{AR}	Repetitive Avalanche Energy	(Note 1)	18	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	6.0	V/ns	
P_{D}	Power Dissipation (T _C = 25°C)		180	W	
	- Derate above 25°C		1.2	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +175	°C	
T _L	Maximum lead temperature for soldering purposes, 1/8∀ from case for 5 seconds		300	°C	

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		0.83	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.24		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		40	°C/W

Symbol	Parameter	Test Conditions	3	Min	Тур	Max	Units
Off Cha	aracteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 250 μA		100			V
ΔBV _{DSS} / ΔΤ _J	Breakdown Voltage Temperature Coefficient I _D = 250 μA, Referenced to 25°C		I to 25°C		0.1		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 100 V, V _{GS} = 0 V				1	μА
		V _{DS} = 80 V, T _C = 150°C				10	μА
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 25 V, V _{DS} = 0 V				100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -25 V, V _{DS} = 0 V				-100	nA
On Cha	racteristics						
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$		2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 24 A			0.03	0.039	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D = 24 A	(Note 4)		31		S
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz			1400 425 85	1800 550 110	pF pF pF
	•				- 00	110	рі
t _{d(on)}	Ing Characteristics Turn-On Delay Time				19	45	ns
t _r	Turn-On Rise Time	V_{DD} = 50 V, I_{D} = 43.5 A, R_{G} = 25 Ω (Note 4, 5)			190	390	ns
t _{d(off)}	Turn-Off Delay Time				90	190	ns
t _f	Turn-Off Fall Time				100	210	ns
Qg	Total Gate Charge	V _{DS} = 80 V, I _D = 43.5 A,			48	62	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = 00 \text{ V}, 10 = 43.3 \text{ A},$ $V_{GS} = 10 \text{ V}$ (Note 4, 5)			9.0		nC
Q _{gd}	Gate-Drain Charge				24		nC
	ource Diode Characteristics a	<u>~</u>	s				
l _S	Maximum Continuous Drain-Source Diode Forward Current				48	Α	
I _{SM}	Maximum Pulsed Drain-Source Diode F					192	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 48 A				1.5	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_S = 43.5 \text{ A},$			98		ns
Q_{rr}	Reverse Recovery Charge	dI _F / dt = 100 A/μs	(Note 4)		360		nC

- **Notes:** 1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 0.345mH, I_{AS} = 48A, V_{DD} = 25V, R_G = 25 Ω , Starting T_J = 25°C 3. $I_{SD} \le 43.5A$, $di/dt \le 300A/\mu_S$, $V_{DD} \le BV_{DSS}$, Starting T_J = 25°C 4. Pulse Test : Pulse width $\le 300\mu_S$, Duty cycle $\le 2\%$ 5. Essentially independent of operating temperature

Typical Characteristics

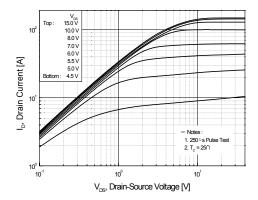


Figure 1. On-Region Characteristics

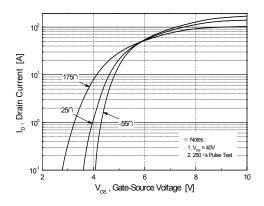


Figure 2. Transfer Characteristics

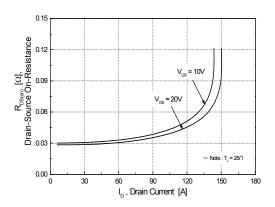


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

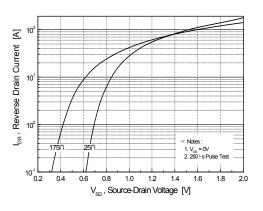


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

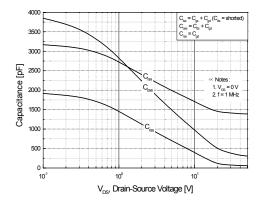


Figure 5. Capacitance Characteristics

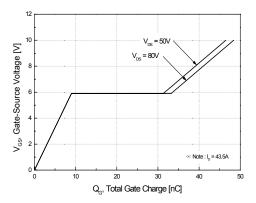


Figure 6. Gate Charge Characteristics



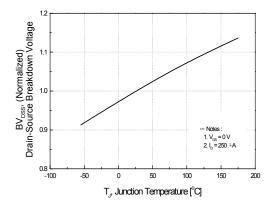
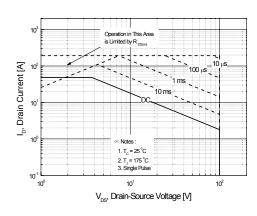


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



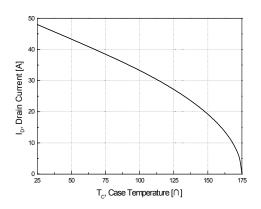


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

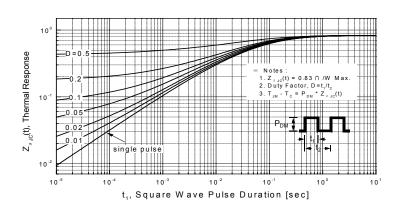
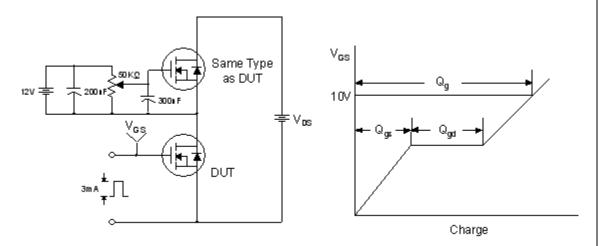
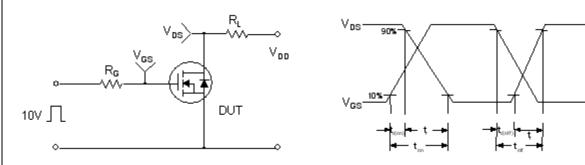


Figure 11. Transient Thermal Response Curve

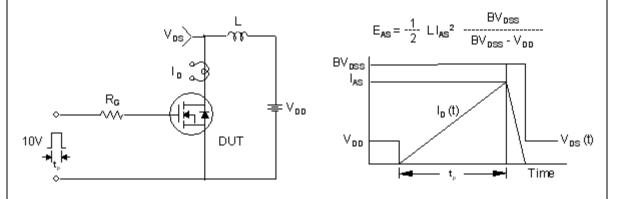
Gate Charge Test Circuit & Waveform



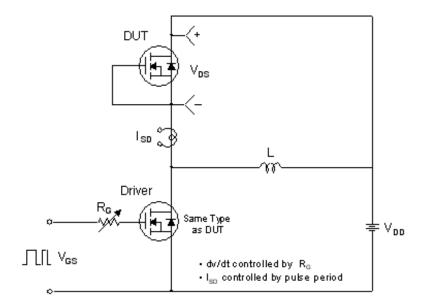
Resistive Switching Test Circuit & Waveforms

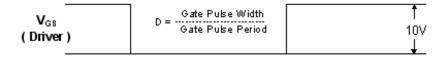


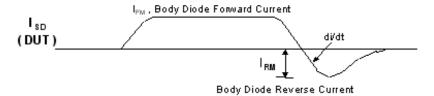
Unclamped Inductive Switching Test Circuit & Waveforms

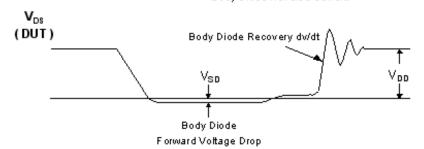


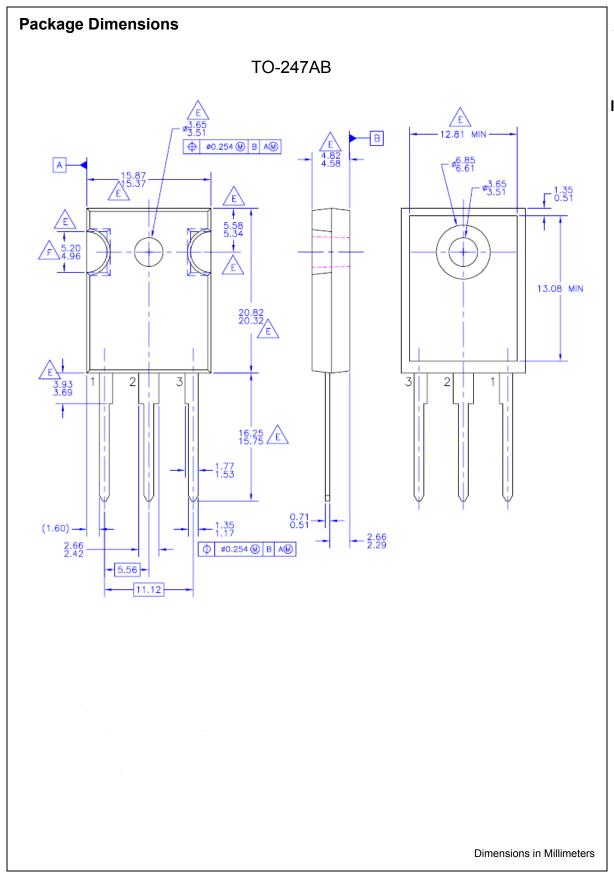
Peak Diode Recovery dv/dt Test Circuit & Waveforms















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